

# Supporting Information

Liehui Ge<sup>1</sup>, Lijie Ci<sup>2</sup>, Anubha Goyal<sup>2</sup>, Rachel Shi<sup>1</sup>, L. Mahadevan<sup>3</sup>, Pulickel Ajayan<sup>2</sup> and

Ali Dhinojwala<sup>1\*</sup>

<sup>1</sup>*Department of Polymer Science, The University of Akron, Akron, OH 44325*

<sup>2</sup>*Department of Mechanical Engineering and Materials Science, Rice University,  
Houston, TX 77005*

<sup>3</sup>*School of Engineering and Applied Sciences, Harvard University, Cambridge, MA  
02138*

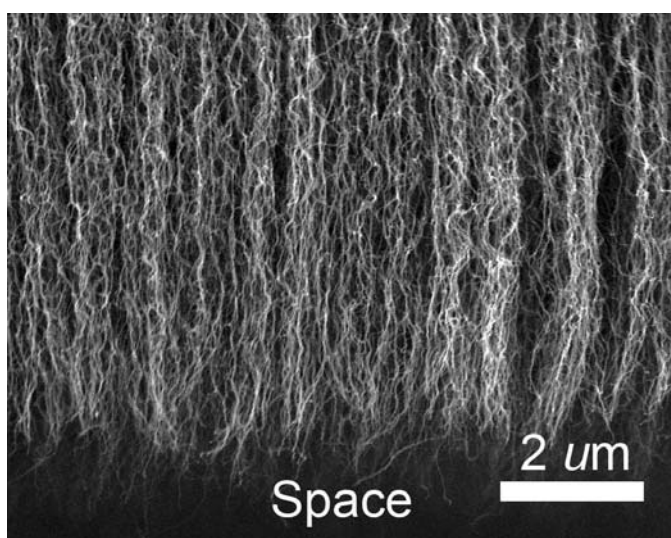


Figure S1: SEM images showing the side view of the surface of the VA-CNT array before contact.

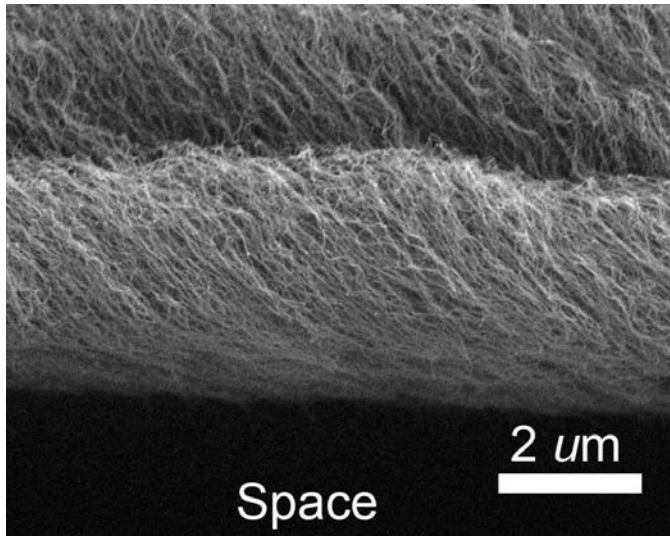


Figure S2: SEM images showing the side view of the surface of VA-CNT array after contact.

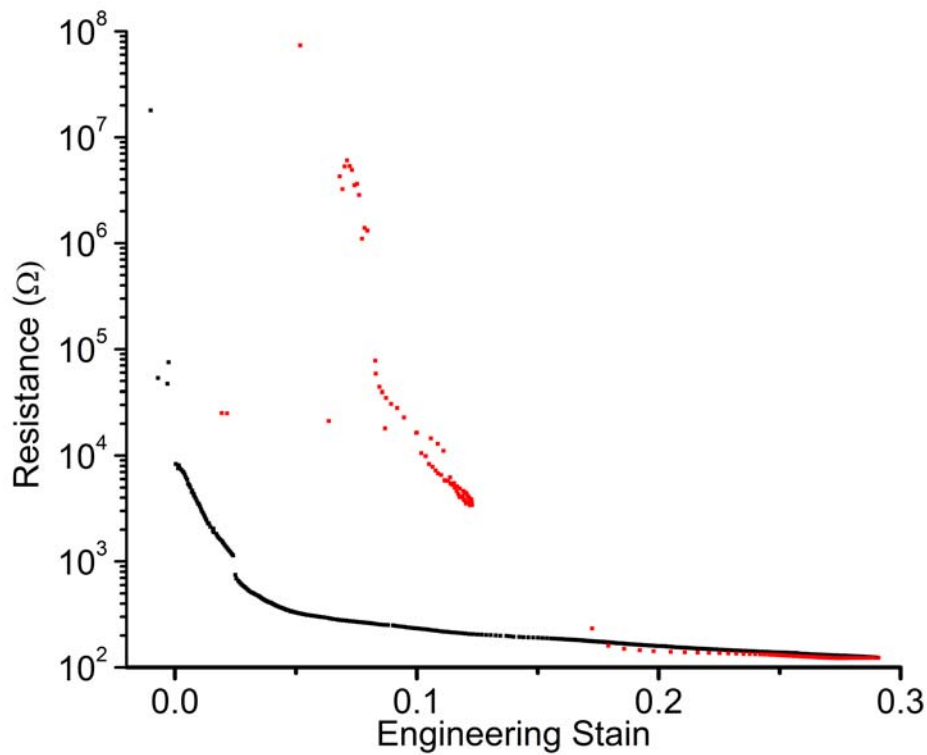


Figure S3: Change in resistance when VA-CNT array is compressed (black) and retracted after bringing the array in contact with ITO glass. The resistance ( $R_{\min}$ ) of sample that was compressed to 80-90% strain was 95 ohms. The resistance of the direct ITO-ITO contact was 45 ohms.